

AOMR62818

80V N-Channel AlphaSGT™

General Description

- Trench Power MOSFET AlphaSGTTM technology
- Optimize TCoB
- Best in Class Low R_{DS(ON)}
- Low Switching Loss
- · Logic Level Gate Drive
- RoHS and Halogen-Free Compliant

Applications

- Synchronous Rectification
- High Frequency DC/DC Converters

Orderable Part Number

Product Summary

 $\begin{array}{lll} V_{DS} & 80V \\ I_{D} \; (at \; V_{GS} \! = \! 10V) & 78A \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 10V) & < 6.6 m\Omega \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 4.5V) & < 9.5 m\Omega \end{array}$

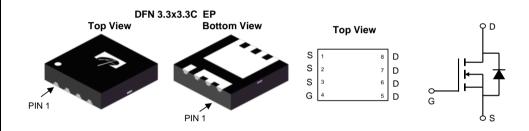
100% UIS Tested 100% Rg Tested

Max Tj=175°C

Form



Minimum Order Quantity



Package Type

AOMR62818		DFN 3.3x3.3C	Tape & Reel	3000	
Absolute Maximum	Ratings T _A =25°C unl	ess otherwise noted	<u>t</u>		
Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		V_{DS}	80	V	
Gate-Source Voltage		V_{GS}	±20	V	
Continuous Drain	T _C =25°C		78		
Current	T _C =100°C	I _D	55	А	
Pulsed Drain Current ^C		I _{DM}	312		
Continuous Drain Current	T _A =25°C		18	A	
	T _A =70°C	IDSM	15	A	
Avalanche Current ^C		I _{AS}	42	A	
Avalanche energy	L=0.1mH ^C	E _{AS}	88	mJ	
	T _C =25°C	P _D	88	W	
Power Dissipation ^B	T _C =100°C	L D	44	VV	
	T _A =25°C	D	5	W	
Power Dissipation ^A	T _A =70°C	P _{DSM}	3.5	VV	
Junction and Storage Temperature Range		T _J , T _{STG}	-55 to 175	°C	

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	D	25	30	°C/W			
Maximum Junction-to-Ambient AD	Steady-State $R_{\theta JA}$		50	60	°C/W			
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	1.4	1.7	°C/W			



Electrical Characteristics (T_{.i}=25°C unless otherwise noted)

Symbol	Parameter	rameter Conditions		Тур	Max	Units				
STATIC PARAMETERS										
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	80			V				
ı	Zero Gate Voltage Drain Current	V _{DS} =80V, V _{GS} =0V			1	μΑ				
DSS	Zelo Gate Voltage Diam Guirent	T _J =55°C			5					
I_{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} =±20V			±100	nA				
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	1.3	1.8	2.3	V				
	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =18A		5.5	6.6	mΩ				
R _{DS(ON)}		T _J =125°C		9.5	11.5	11122				
		V_{GS} =4.5V, I_D =15A		7.5	9.5	mΩ				
g _{FS}	Forward Transconductance	V_{DS} =5V, I_D =18A		65		S				
V_{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V		0.7	1	V				
Is	Maximum Body-Diode Continuous Cur			78	Α					
DYNAMIC	PARAMETERS									
C _{iss}	Input Capacitance			2420		pF				
Coss	Output Capacitance	V_{GS} =0V, V_{DS} =40V, f=1MHz		280		pF				
C _{rss}	Reverse Transfer Capacitance			15		pF				
R_g	Gate resistance	f=1MHz	0.6	1.35	2	Ω				
SWITCHI	NG PARAMETERS									
Q _g (10V)	Total Gate Charge			34	48	nC				
Q _g (4.5V)	Total Gate Charge	V _{GS} =10V, V _{DS} =40V, I _D =18A		15	23	nC				
Q_{gs}	Gate Source Charge	V _{GS} =10V, V _{DS} =40V, I _D =10A		7.5		nC				
Q_{gd}	Gate Drain Charge			4		nC				
Q _{oss}	Output Charge	V_{GS} =0V, V_{DS} =40V		31		nC				
$t_{D(on)}$	Turn-On DelayTime			7		ns				
t _r	Turn-On Rise Time	V_{GS} =10V, V_{DS} =40V, R_L =2.5 Ω ,		4		ns				
$t_{D(off)}$	Turn-Off DelayTime	$R_{GEN}=3\Omega$		30		ns				
t _f	Turn-Off Fall Time	<u> </u>		5		ns				
t _{rr}	Body Diode Reverse Recovery Time	I _F =18A, di/dt=500A/μs		24		ns				
Q_{rr}	Body Diode Reverse Recovery Charge	l _F =18A, di/dt=500A/μs		100		nC				

A. The value of $R_{\theta,IA}$ is measured with the device mounted on $1in^2$ FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C. The Power dissipation P_{DSM} is based on R _{6JA} t≤ 10s and the maximum allowed junction temperature of 175 °C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.

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B. The power dissipation P_D is based on $T_{J(MAX)} = 175^{\circ}$ C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(MAX)}$ =175 $^{\circ}$ C.

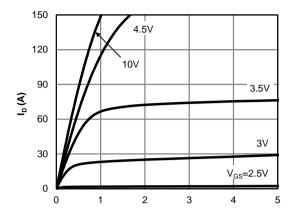
D. The R_{BJA} is the sum of the thermal impedance from junction to case R_{BJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

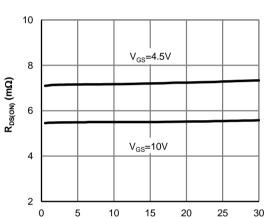
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$ =175° C. The SOA curve provides a single pulse rating. G. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C.



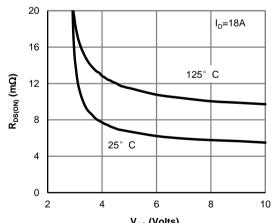
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



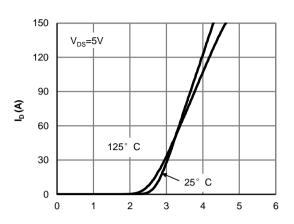
 ${
m V_{DS}}$ (Volts) Figure 1: On-Region Characteristics (Note E)



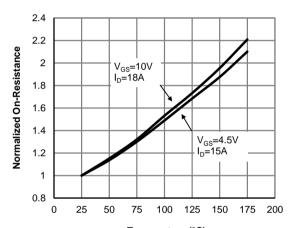
I_D (A) Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



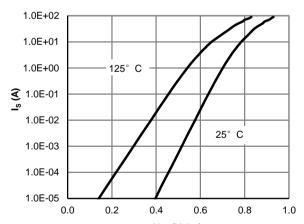
V_{GS} (Volts) Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)



 V_{GS} (Volts) Figure 2: Transfer Characteristics (Note E)



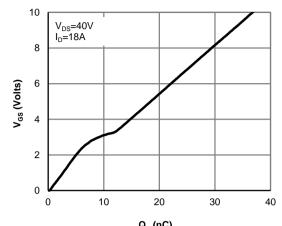
Temperature (°C)
Figure 4: On-Resistance vs. Junction
Temperature (Note E)



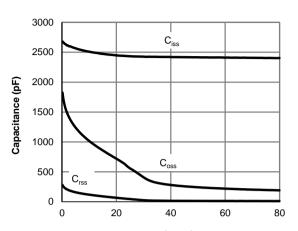
V_{SD} (Volts) Figure 6: Body-Diode Characteristics (Note E)



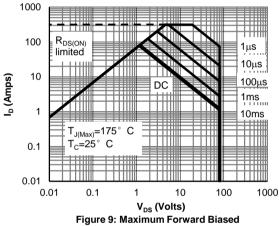
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



 $\rm Q_{\rm g}$ (nC) Figure 7: Gate-Charge Characteristics



V_{DS} (Volts)
Figure 8: Capacitance Characteristics



Safe Operating Area (Note F)

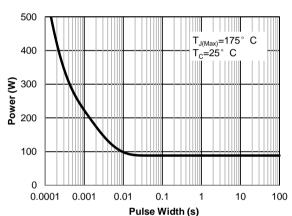
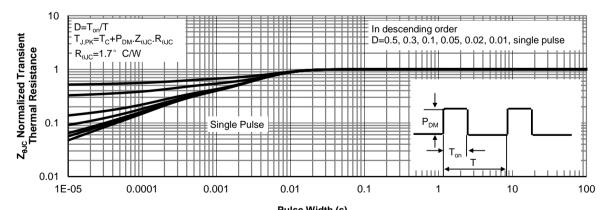


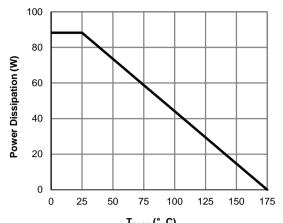
Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)



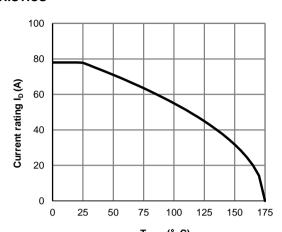
Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



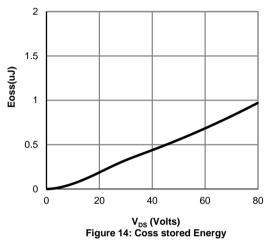
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

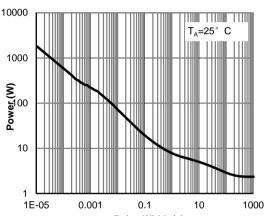


T_{CASE} (° C)
Figure 12: Power De-rating (Note F)

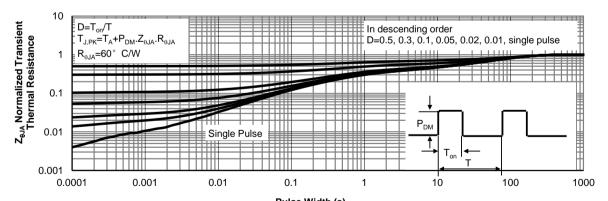


T_{CASE} (° C)
Figure 13: Current De-rating (Note F)





Pulse Width (s) Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note G)



Pulse Width (s)
Figure 16: Normalized Maximum Transient Thermal Impedance (Note G)

Figure A: Gate Charge Test Circuit & Waveforms

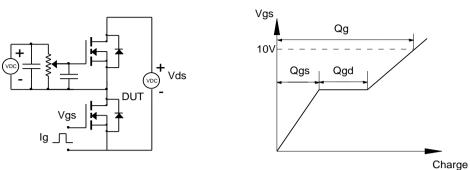


Figure B: Resistive Switching Test Circuit & Waveforms

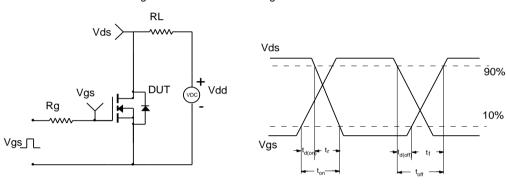


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

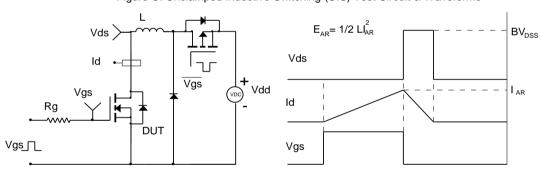
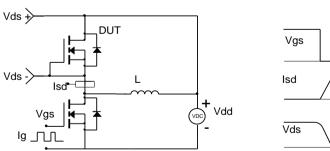
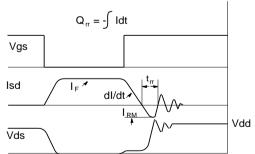


Figure D: Diode Recovery Test Circuit & Waveforms





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